

**Search Notes**

Application/Control No.

10/659,276

Examiner

Tuan H. Le

Applicant(s)/Patent under  
Reexamination

NAKANISHI, YUTAKA

Art Unit

2622

**SEARCHED**

Class	Subclass	Date	Examiner
348	373- 376,333,	11/15/2006	TL
D16	all	11/16/2006	TL
386	117-118,1	11/17/2006	TL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor name search	11/15/2006	TL
US-PGPUB,USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB	11/15/2006	TL
INSPEC (same search key as in EAST)	11/15/2006	TL